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U.S. PATENT ATTY. DOCKET NO. APPLICATION NO. INFORMATION DISCLOSURE 4686-003 10/743,335 CITATION IN AN **APPLICANT APPLICATION** Hiroyuki KUWANA DEC 0 2 200 FILING DATE **GROUP** (PTO-1449) December 23, 2003 3711 **U.S. PATENT DOCUMENTS** FILING EXAMINER'S CLASS SUBCLASS NAME PATENT NO. DATE DATE INITIALS FOREIGN PATENT DOCUMENTS Translation **EXAMINER'S SUBCLASS CLASS** COUNTRY PATENT NO. DATE Yes INITIALS JP-A-2003-X ARK JP 7/2003 190637 ACUL X JΡ JP-A-2002-95870 4/2002 X All 2/2002 JΡ JP-A-2002-35428 JP-A-2001-X APPL JΡ 11/2001 . 331721 OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.) DATE CONSIDERED EXAMINER EXAMINER: Initialif reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.